



Product Change Notification / ASER-19HIWO872

Date:

30-Sep-2022

Product Category:

8-bit Microcontrollers

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4748 Final Notice: Qualification of MTAI as an additional assembly site for selected ATMEGA324PBxxx and PIC16F1xxx device families available in 44L TQFP (10x10x1mm) package.

Affected CPNs:

[ASER-19HIWO872_Affected_CPN_09302022.pdf](#)
[ASER-19HIWO872_Affected_CPN_09302022.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.
Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of MTAI as an additional assembly site for selected ATMEGA324PBxxx and PIC16F1xxx device families available in 44L TQFP (10x10x1mm) package.

Pre and Post Change Summary:

	Pre Change	Post Change
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the applicable selections.



QUALIFICATION PLAN SUMMARY

PCN #: ASER-19HIWO872

**Date:
Aug 19, 2021**

Qualification of MTAI as an additional assembly site for selected ATMEGA324PBxxx and PIC16F1xxx device families available in 44L TQFP (10x10x1mm) package. This is a Q100 grade 1 qualification.

Purpose: Qualification of MTAI as an additional assembly site for selected ATMEGA324PBxxx and PIC16F1xxx device families available in 44L TQFP (10x10x1mm) package. This is a Q100 grade 1 qualification.

CCB: 4748

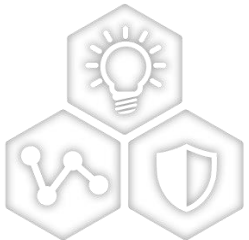
<u>Misc.</u>	Assembly site	MTAI
	BD Number	BDM-002935 rev.A
	MP Code (MPC)	59B18FT4XVA1
	Part Number (CPN)	ATMEGA324PB-ABTVAO
<u>Lead-Frame</u>	Paddle size	180 x 180 mils
	Material	C7025
	DAP Surface Prep	Bare Copper
	Treatment	Yes
	Process	Stamped
	Lead-lock	No
	Part Number	10104404
	Lead Plating	Matte Tin
<u>Bond Wire</u>	Material	Au
<u>Die Attach</u>	Part Number	3280
	Conductive	Yes
<u>MC</u>	Part Number	G700
<u>PKG</u>	PKG Type	TQFP
	Pin/Ball Count	44
	PKG width/size	10x10x1.0 mm

Test Name	Conditions	Reliability Stress Read Point Grade 1: -40°C to +125°C (MCHP E Temp)	Pre & Post Reliability Stress Test Temperature Grade 1: -40°C to +125°C (MCHP E Temp)	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL Test Site	Special Instructions
Standard Pb-free Solderability	J-STD-002D ; Perform 8 hours of steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.			22	5	1	27	>95% lead coverage	5			Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
Wire Bond Pull - WBP	Mil. Std. 883-2011			5	0	1	5	0	5			30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001			5	0	1	5	0	5			30 bonds from a min. 5 devices.
Physical Dimensions	Measure per JESD22 B100 and B108			10	0	3	30	0	5			
External Visual	Mil. Std. 883-2009/2010			All devices prior to submission for qualification testing	0	3	ALL	0	5			
HTSL (High Temp Storage Life)	JESD22-A103 +175°C	Grade 1: 500 hrs (+175°C)	Grade 1: +25°C, +85°C, +125°C	45	5	1	50	0	21 - 83	MPHL	MPHL	Spares should be properly identified.
Preconditioning - Required for surface mount devices	J-STD-020JESD22-A113+150°C Bake for 24 hours, moisture loading requirements per MSL level (MSL1/260) + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type. Perform SAM analysis using 45 samples per lot.		Grade 1: +25°C	231	15	3	738	0	15	MPHL	MPHL	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test. 45 parts from one lot to be used for PTC test (for devices requiring
HAST	JESD22-A101 or A110 +130°C/85% RH for 96 hrs	Grade 1: 96 hrs (+130°C/ 85% RH)	Grade 1: +25°C, +85°C, +125°C	77	5	3	246	0	10 - 14	MPHL	MPHL	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
UHAST	JESD22-A102, A118, or A101 +130°C/85% RH for 96 hrs o	Grade 1: 96 hrs (+130°C/ 85% RH)	Grade 1: +25°C	77	5	3	246	0	10	MPHL	MPHL	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	JESD22-A104 and Appendix 3 -65°C to +150°C	Grade 1: 500 cycles (- 65°C to 150°C)	Grade 1: +85°C, +125°C	77	5	3	246	0	15 - 60	MPHL	MPHL	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.

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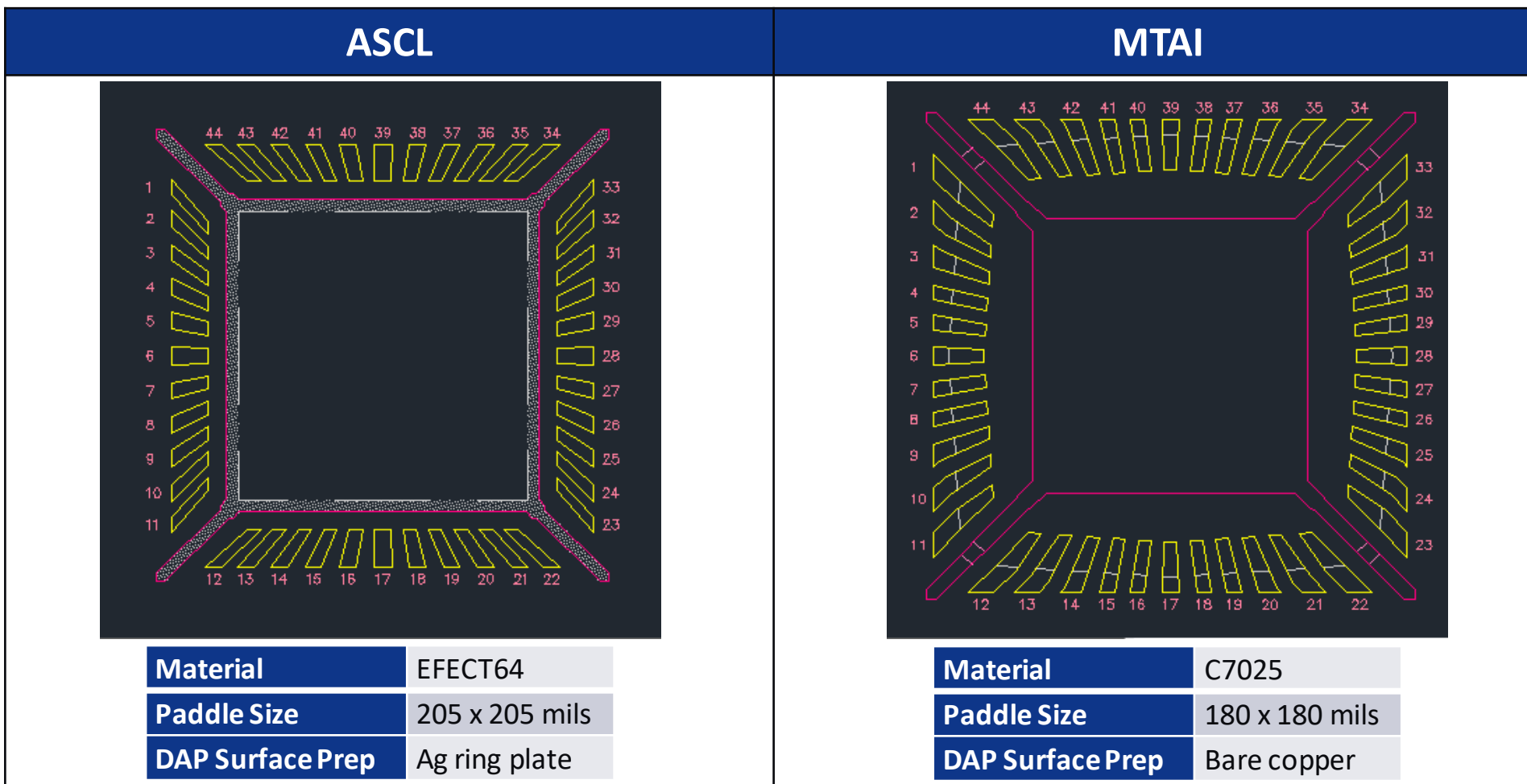


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Lead Frame Comparison



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Affected Catalog Part Numbers(CPN)

ATMEGA324PB-ANR
ATMEGA324PB-AUR
PIC16F15274-E/PT
PIC16F15275-E/PT
PIC16F15276-E/PT
PIC16F15274-I/PT020
PIC16F15274-I/PT
PIC16F15275-I/PT
PIC16F15276-I/PT
PIC16F18075-I/PT
ATMEGA324PB-AU
ATMEGA324PB-AN
ATMEGA324PB-ABTVAO